

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10786164	BEAN ET AL.
	Examiner	Art Unit
	Chin-Shue, Alvin C	3634

### SEARCHED

Class	Subclass	Date	Examiner
182	18	4/27/07	acs

### SEARCH NOTES

Search Notes	Date	Examiner

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner